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## Evaluation of Carrier Mobility of Phthalocyanine Films in $\text{NH}_3$ and $\text{NO}_2$ Gas Atmosphere by Field Effect Measurement

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The carrier mobility of titanyl-phthalocyanine (TiOPc) films was evaluated based on field-effect measurements at the presence of electron acceptor gas ( $\text{NO}_2$ ) and electron donor gas ( $\text{NH}_3$ ) molecules. The increase in carrier density due to  $\text{NO}_2$  adsorption was found to be a dominant factor of an increase in the dark electric conductivity. On the other hand, the decrease in conductivity at the presence of  $\text{NH}_3$  gas was contributed by the decrease in both carrier mobility and carrier density. The adsorbed gas molecules were found to play an important role not only in carrier density but also in the carrier transport.

**Keywords:** Field-Effect Transistor (FET); gas adsorption; titanyl-phthalocyanine; carrier mobility

### INTRODUCTION

The dark electric conductivity of metal phthalocyanines (MPc) is easily modified by the presence of gases [1]. Most MPc compounds are known to show *p*-type semiconducting behavior [1, 2]. Their conductivities increase at the presence of electron acceptor gases such as  $\text{O}_2$  and  $\text{NO}_x$ , and decrease with electron donor gases such as  $\text{NH}_3$ . These experimental results are explained by the change of the hole concentration in the MPc films [3]. There have been only a few reports which consider the effect of gas molecules on the carrier transport mechanism, although there are many reports on the measurement of carrier mobility of organic semiconductors. Assadi *et al.* showed that the hole mobility of poly (3-hexylthiophen) is affected by the atmosphere for the measurement [4]. More recently Kudo *et al.* described that the carrier mobility of MPc films is affected by film structure and by oxygen gas exposure [5]. These works lead to a considerable interest in the effect of gas molecules on the carrier trans-

port mechanism in organic films.

In the present study, we evaluated the field-effect carrier mobility of titanyl-phthalocyanine (TiOPc) films at the presence of  $\text{NH}_3$  and  $\text{NO}_2$  gas molecules. The effect of gas adsorption on the carrier density and carrier transport will be discussed.

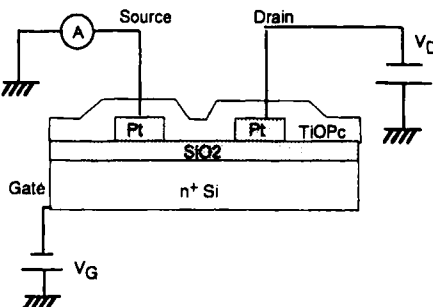


FIGURE 1. Schematic view of the FET

Figure 1 shows a schematic view of the FET cell. Highly doped  $n^+$ -Si(111) plate was used as the gate electrode on which the  $\text{SiO}_2$  layer with the thickness of 180 nm was formed by thermal oxidation. The interdigital Pt electrodes with the thickness of 30 nm were prepared on the surface, and served as drain and source electrodes. The electrode consisted of 32 pairs with 25  $\mu\text{m}$  in spacing and 6 mm in width. The TiOPc films were prepared in a vacuum chamber with a base pressure of  $1 \times 10^{-4}$  Pa on the substrate. The growth rate and thickness were about 0.4 nm/min and 40 nm, respectively. The specimens thus prepared were taken out from the growth chamber and introduced into the measurement chamber immediately.

The FET characteristics of the specimens were investigated in the chamber in which the atmosphere could be controlled. The standard gas of  $\text{NH}_3/\text{N}_2$  (100 ppm, Nippon Sanso) and  $\text{NO}_2/\text{N}_2$  (100 ppm, Nippon Sanso) was diluted at an appropriate concentration with pure  $\text{N}_2$  gas (99.999%, Nippon Sanso) using a mass flow controlled gas blender (Stec, SECB-2), and was introduced into the measurement chamber.

The mobility was calculated by fitting the curves observed to the following equation available for MOS-FET [6]:

$$I_D(\text{sat}) = \mu WC (V_G - V_T)^2 / 2L \quad (1)$$

Here,  $I_D(\text{sat})$  is the saturated drain current,  $\mu$  is the mobility,  $V_G$  is the voltage applied to the gate,  $V_T$  is the threshold voltage,  $L$ ,  $W$  and  $C$  are the channel

length, channel width, and capacitance of the gate insulator, respectively.

In order to estimate the carrier density in gas atmosphere, we measured the dark conductivity of TiOPc films grown on glass substrates with inter digital gold electrodes. The carrier density,  $N$ , was estimated by the following equation using the measured dark conductivity,  $\sigma$ , and carrier mobility,  $\mu$ , which was obtained by Eq.(1):

$$N = \sigma / e \mu . \quad (2)$$

## RESULTS AND DISCUSSION

Figures 2(a) and 2(b) show FET properties of the device measured in vacuum and  $\text{NO}_2$  (20 ppm) atmosphere, respectively. The saturated current is found to increase in  $\text{NO}_2$  atmosphere, indicating that the carrier mobility was modified by  $\text{NO}_2$  gas adsorption. The carrier mobility evaluated using equation (1) was  $1.1 \times 10^{-5} \text{ cm}^2/\text{Vs}$  in vacuum and  $2.4 \times 10^{-5} \text{ cm}^2/\text{Vs}$  in 20 ppm  $\text{NO}_2$ . The conductivity of the films measured in vacuum and  $\text{NO}_2$  atmosphere exhibited an increase of 770 times in  $\text{NO}_2$  (20 ppm) atmosphere with an increase of 2.2 times in carrier mobility. Equation (2) suggests that the carrier density increased by 350 in  $\text{NO}_2$ . In the case of the adsorption of electron acceptor gas molecules such as  $\text{NO}_2$ , the increase in carrier density was a dominant factor of an increase in the dark electric conductivity. On the other hand, electron donor gas molecules such as  $\text{NH}_3$  were found to influence the carrier transport as well

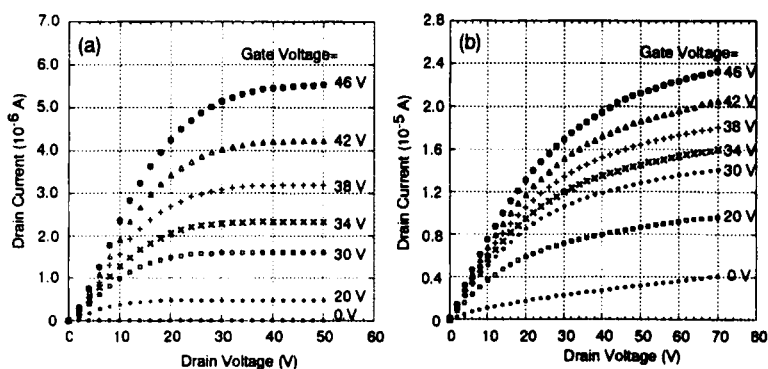


FIGURE 2. FET characteristics of TiOPc films in vacuum (a) and in  $\text{NO}_2$  (20 ppm) atmosphere (b).

TABLE I. Evaluated values of electric conductivity, carrier mobility and carrier density in vacuum and NH<sub>3</sub> atmosphere.

	conductivity		carrier mobility		carrier density	
	$\sigma$ (S/cm)	$\sigma_{\text{gas}} / \sigma_{\text{vac}}$	$\mu$ (cm <sup>2</sup> /Vs)	$\mu_{\text{gas}} / \mu_{\text{vac}}$	$N$ (cm <sup>-3</sup> )	$N_{\text{gas}} / N_{\text{vac}}$
vacuum	$1.7 \times 10^{-8}$	1	$1.2 \times 10^{-4}$	1	$8.9 \times 10^{14}$	1
NH <sub>3</sub> (50 ppm)	$3.1 \times 10^{-9}$	0.18	$5.6 \times 10^{-5}$	0.47	$3.4 \times 10^{14}$	0.38
NH <sub>3</sub> (100 ppm)	$4.3 \times 10^{-10}$	0.025	$2.1 \times 10^{-5}$	0.18	$1.2 \times 10^{14}$	0.14

as carrier density as shown in Table I.

Table I summarizes the values of conductivity, carrier mobility, and carrier density measured in vacuum and in NH<sub>3</sub> atmosphere. The adsorbed NH<sub>3</sub> gas molecules were found to decrease both the carrier mobility and carrier density, which resulted in the decrease in dark conductivity.

In summary, the field-effect mobility of TiOPc films were evaluated at the presence of electron acceptor gas (NO<sub>2</sub>) and electron donor gas (NH<sub>3</sub>). The hole mobility was found to be modified significantly by the adsorption of gas molecules. In the case of the NO<sub>2</sub> gas adsorption, the increase in conductivity is found to be governed dominantly by the increase in carrier density. On the other hand, the decrease in conductivity at the presence of NH<sub>3</sub> gas is ascribed to the decrease in carrier mobility as well as in carrier density.

**Acknowledgments**

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**References**

[1] A. W. Snow and W. R. Barger, in Phthalocyanines vol. 1 eds. by C. C. Leznoff and A. B. P. Lever (VCH, New York, 1989) Chapter 5.  
[2] D. Wöhrle, L. Kreienhoop, and D. Schlettwein, in Phthalocyanines vol. 4 eds. by C. C. Leznoff and A. B. P. Lever (VCH, New York, 1996) Chapter 6.  
[3] M. Passard, C. Maleysson, A. Pauly, S. Dogo, J. -P. Germain, and J. -P. Blanc, Sensors Actuators B 18–19 (1994) 489.  
[4] A. Assadi, G. Gustafsson, M. Willander, C. Svensson, and O. Inganäs, Synthetic Metals 37 (1990) 123.  
[5] K. Kudo, T. Sumimoto, K. Hiraga, S. Kuniyoshi, and K. Tanaka, Jpn. J. Appl. Phys. 36 11 (1997) 6994.  
[6] S. M. Sze, Physics in Semiconductor Devices (John Wiley & Sons, New York, 1981) Chapter 8.